Surface Mount Devices Lead free device Surface Mount packaging for automated assembly Agency recognition: UL Applications

Almost anywhere there is a low voltage power supply, up to 30V and a load to be protected, including:

Computer mother board, Modem. USB hub PDAs & Charger, Analog & digital line card Digital cameras, Disk drivers, CD-ROMs,

1210



Performance Specification

Model	V _{max}	I _{max}	lhold	l _{trip}	Pd	Maximum Time To Trip		Resistance	
Model			@25℃	@25℃	Max.	Current	Time	Ri _{min}	R1max
	(Vdc)	(A)	(A)	(A)	(W)	(A)	(Sec)	(Ω)	(Ω)
BpS10-050-30	30.0	100	0.05	0.15	0.6	0.3	1.50	2.800	50.000
BpS10-100-30	30.0	100	0.10	0.30	0.6	0.5	0.60	0.800	15.000
BpS10-200-30	30.0	100	0.20	0.40	0.6	8.0	0.02	0.400	5.000
BpS10-350-06	6.0	100	0.35	0.75	0.6	8.0	0.20	0.200	1.300
BpS10-500-13	13.2	100	0.50	1.00	0.6	8.0	0.10	0.180	0.900
BpS10-750-06	6.0	100	0.75	1.50	0.6	8.0	0.10	0.070	0.400
BpS10A01.10-06	6.0	100	1.10	2.20	0.6	8.0	0.30	0.050	0.210
BpS10A01.50-06	6.0	100	1.50	3.00	0.6	8.0	0.50	0.030	0.110

Ihold = Hold Current. Maximum current device will not trip in 25℃ still air.

Itrip = Trip Current. Minimum current at which the device will always trip in 25℃ still air.

Vmax = Maximum operating voltage device can withstand without damage at rated current (Imax).

Imax = Maximum fault current device can withstand without damage at rated voltage (Vmax).

Pd = Maximum power dissipation when device is in the tripped state in 25℃ still air environment at rated volta ge.

Rimin/max = Minimum/Maximum device resistance prior to tripping at 25℃.

R1_{max} = Maximum device resistance is measured one hour post reflow.

CAUTION: Operation beyond the specified ratings may result in damage and possible arcing and flame.

Environmental Specifications

Test	Conditions	Resistance change	
Passive aging	+85°C, 1000 hrs.	±5% typical	
Humidity aging	+85℃, 85% R.H. , 168 hours	±5% typical	
Thermal shock	+85℃ to -40℃, 20 times	±33% typical	
Resistance to solvent	MIL-STD-202,Method 215	No change	
Vibration	MIL-STD-202,Method 201	No change	
Ambient operating conditions :	- 40 ℃ to 85 ℃		
Maximum surface temperature of th	e device in the tripped state is 125 $^{\circ}$		

AGENCY APPROVALS : U.L pending

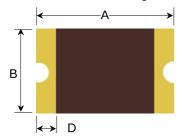
I_{hold} versus temperature

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Model	Maximum ambient operating temperature (Tmao) vs. hold current (Ihold)									
Model	-40℃	-20℃	0℃	25℃	40℃	50℃	209	70℃	85℃	
BpS10-050-30	0.08	0.07	0.06	0.05	0.04	0.04	0.03	0.03	0.02	
BpS10-100-30	0.16	0.14	0.12	0.10	0.08	0.07	0.06	0.05	0.03	
BpS10-200-30	0.29	0.26	0.22	0.20	0.16	0.14	0.13	0.11	0.08	
BpS10-350-06	0.47	0.45	0.40	0.35	0.33	0.28	0.24	0.21	0.18	
BpS10-500-13	0.76	0.67	0.58	0.50	0.43	0.40	0.36	0.32	0.28	
BpS10-750-06	1.00	0.97	0.86	0.75	0.64	0.59	0.54	0.48	0.40	
BpS10A01.10-06	1.69	1.48	1.29	1.10	0.88	0.76	0.65	0.57	0.43	
BpS10A01.50-06	2.13	1.92	1.71	1.50	1.26	1.14	1.01	0.89	0.71	

Construction and Dimension (Unit:mm)

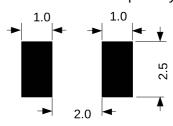
Model	А		E	3	(D	
	Min.	Max.	Min.	Max.	Min.	Max.	Min.
BpS10-050-30	3.00	3.43	2.35	2.80	0.30	0.80	0.30
BpS10-100-30	3.00	3.43	2.35	2.80	0.30	0.80	0.30
BpS10-200-30	3.00	3.43	2.35	2.80	0.30	0.80	0.30
BpS10-350-06	3.00	3.43	2.35	2.80	0.30	0.80	0.30
BpS10-500-13	3.00	3.43	2.35	2.80	0.30	0.80	0.30
BpS10-750-06	3.00	3.43	2.35	2.80	0.30	0.80	0.30
BpS10A01.10-06	3.00	3.43	2.35	2.80	0.30	0.80	0.30
BpS10A01.50-06	3.00	3.43	2.35	2.80	0.60	1.40	0.30

Dimensions & Marking





Recommended pad layout (mm)



Termination pad characteristics

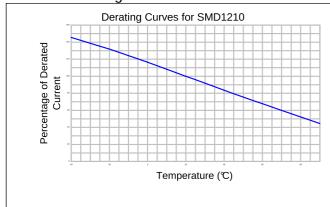
Terminal pad materials: Tin-Plated Nickle-Copper or Gold-Plated Nickle-Copper

Terminal pad solderability: Meets EIA specification RS186-9E and ANSI/J-STD-002 Category 3.

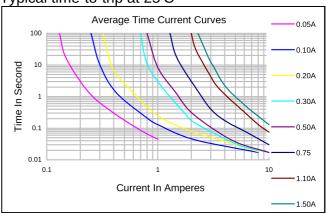
Rework

Use standard industry practices, the removal device must be replaced with a fresh one.

Thermal derating curve



Typical time-to-trip at 25℃



∕!`` WARNING:

- · Use PPTC beyond the maximum ratings or improper use may result in device damage and possible electrical arcing and flame.
- · PPTC are intended for protection against occasional over current or over temperature fault conditions and should not be used when repeated fault conditions or prolonged trip events are anticipated.
- · Device performance can be impacted negatively if devices are handled in a manner inconsistent with recommended electronic, thermal, and mechanical procedures for electronic components.
- Use PPTC with a large inductance in circuit will generate a circuit voltage (L di/dt) above the rated voltage of the PPTC.
- · Avoid impact PPTC device its thermal expansion like placed under pressure or installed in limited space.
- · Contamination of the PPTC material with certain silicon based oils or some aggressive solvents can adversely impact the performance of the devices. PPTC SMD can be cleaned by standard methods.
- Requests that customers comply with our recommended solder pad layouts and recommended reflow profile. Improper board layouts or reflow profile could negatively impact solderability performance of our devices.